ADVANTEST

D3186/3286
Pulse Pattern Generator/Error Detector

150 Mbps to 12.5 Gbps Error Performance Test System Suitable for SDH/SONET



103186/3286



To accommodate transmission of large-capacity information in the coming multimedia generation, ultra high-speed digital telecommunications networks are being constructed. For evaluation and analysis of O/E and E/O modules and ultra high-speed logic devices used for multiplexers and repeaters for telecommunications systems, a signal source with high speed and high quality is necessary. The D3186 Pulse Pattern Generator/D3286 **Error Detector offers excellent waveforms** with high speed and high quality and diverse error detecting functions in an operating frequency range from 150 Mbps to 12.5 Gbps. In addition, with the 8 M-bit large capacity memory and ADVANTEST's unique frame pattern generation function, the D3186/D3286 is a new generation of error performance test system which is compatible with STM-1 (155.52 Mbps) to STM-64 (9.95 Gbps) in SDH/SONET.

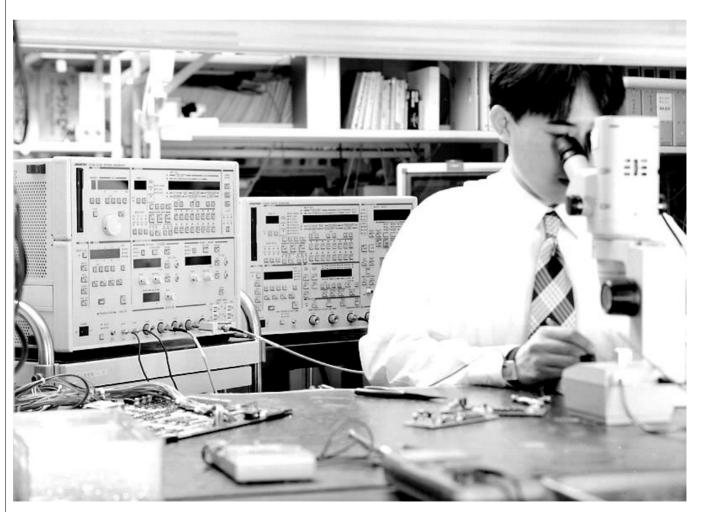
Features

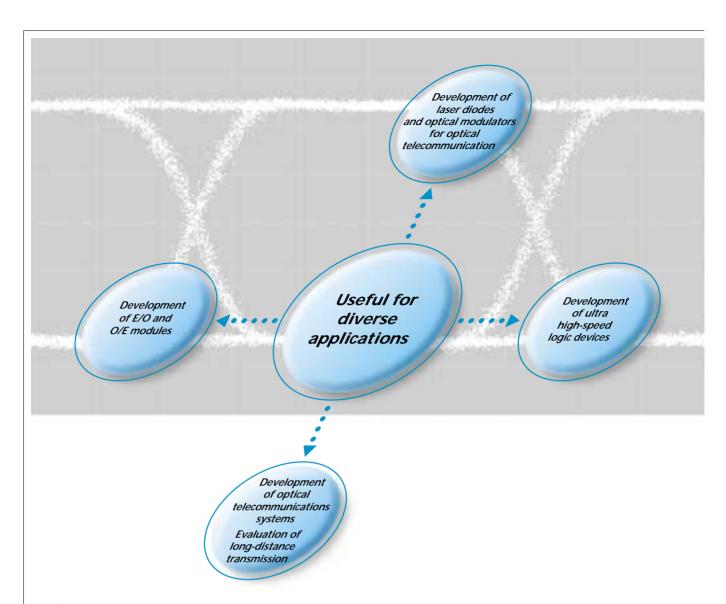
D3186 Pulse Pattern Generator

- Excellent waveform quality
- Generation of SDH/SONET frame patterns (mixed patterns) which are close to actual data
- 8 M-bit memory, 31 stages for PRBS
- Multi-channel output: 2 data channels, 3 clock channels, and 7 sub-rate channels
- Cross point variable for output waveform
- Burst signal output
- 3 Vp-p outputs, effective for EA modulators, etc. (option)

D3286 Error Detector

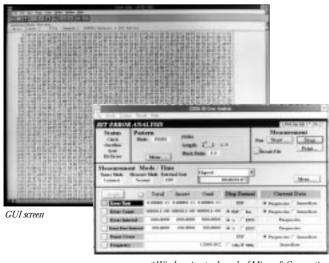
- SDH/SONET frame synchronization suitable for system evaluation
- Error detection with area specification effective for SDH frame and ATM cell measurement
- Burst data measurement effective for loop-back test
- Auto search function which adjusts the most appropriate timing and voltage
- Monitor output of data and clock
- FD drive for storing measurement results and setup data
- GUI environment realizing easy and legible operating environment



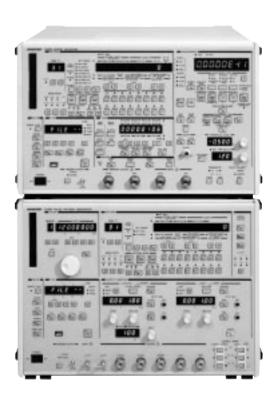


GUI (Graphical User Interface) Provides Simple, Easily Viewed Operating Environment

So that the abundant functions of the D3186/D3286 can be used even more easily, we have designed a graphic operating environment which can be viewed on a personal computer screen. (* for Microsoft Windows environment)



*Windows is a trademark of Microsoft Corporation



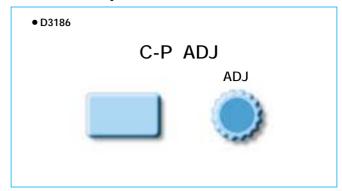
Offers Excellent Waveform Quality

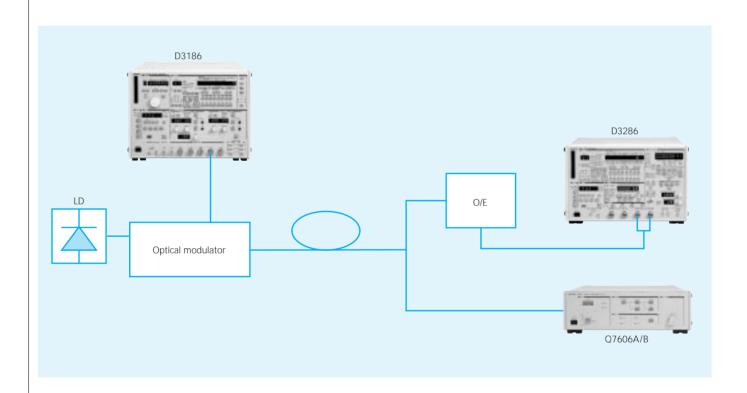
For Performance Evaluation of Optical Components

High waveform quality is essential to evaluate the performance of laser diodes and optical components for optical telecommunication. To meet this demand, the D3186 Pulse Pattern Generator provides excellent waveforms with high speed and high quality. In addition, the D3186 has a wide cross point variable range for the output waveform that makes it easy to control the output waveform correction mark ratio.

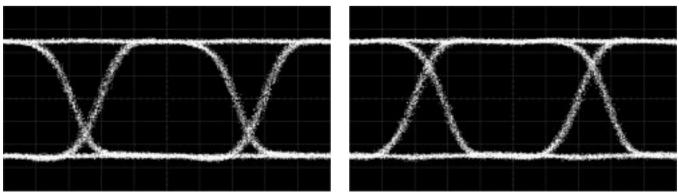
Use As a Modulation Signal Source for Optical Modulators When used together with the Q7606A/B Lightwave Modulation Test Set from ADVANTEST, the D3186 provides a suitable modulation signal source in a chirp measurement system for optical modulators.

Use this function key





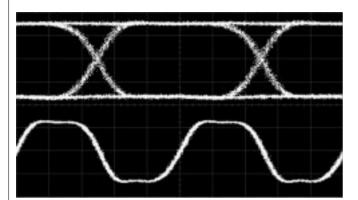
Cross point variable for output waveform (20 to 80%)



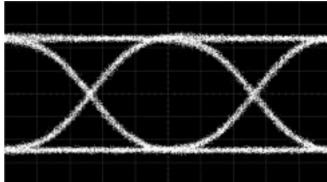
10 Gbit/sec

Excellent Waveform Quality

Through output waveform re-timing, a data output waveform with excellent eye balance, low jitter, and low distortion has been realized.



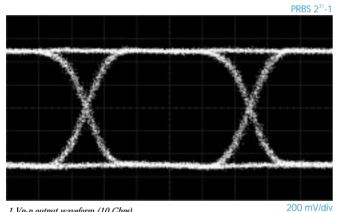
Favorable Matching with 50 ohm Output Impedance With 50 ohm output impedance matching, waveform distortion due to impedance mismatching does not occur even



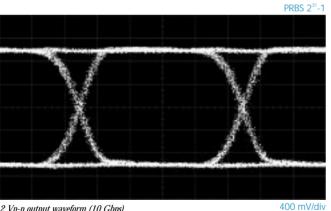
Waveform after passing LPF (9.953 Gbps)

Option 15

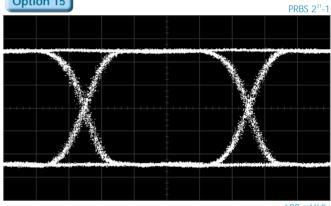
if a mismatched DUT is connected.



1 Vp-p output waveform (10 Gbps)



2 Vp-p output waveform (10 Gbps)



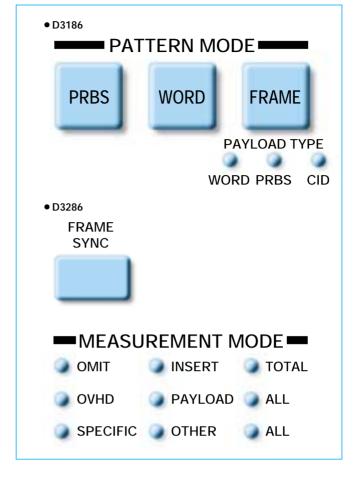
3 Vp-p output waveform (10 Gbps)

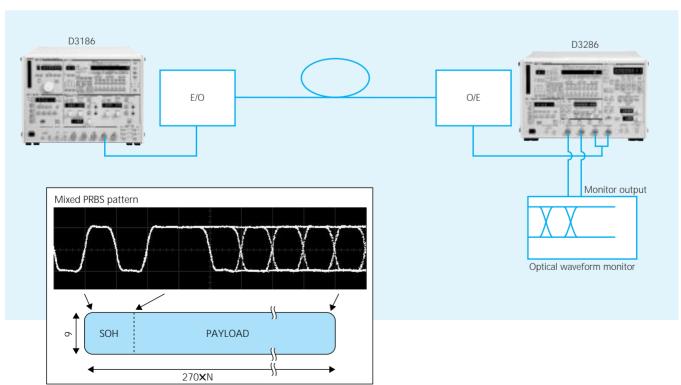
Generation of SDH/SONET Frame Patterns Close to Actual Data

For Evaluation of Optical Transmission Equipment and E/O and O/E Modules

In O/E and E/O tests of the SDH/SONET system, testing at the frame level is required. In addition to the large WORD memory with 8 M-bit length, the D3186 Pulse Pattern Generator is provided with an optional function to insert WORD patterns in the header section of the STM frame and arbitrary PRBS in the payload section, realizing test patterns which are very close to actual data. Of course, the D3286 error detector can measure errors at the header and payload sections separately. In addition, the D3286 powerfully supports location of cause of errors by means of the frame synchronization function and specific area error measurement function.

Use this function key





Generation of SDH/SONET frame pattern virtually identical with real data

Applicable to Fiber Loop Testing

In long-distance transmission testing, fiber loop-based transmission evaluation is performed. In this test, bit error measurement for irregular burst condition data is essential. The D3186 pulse pattern generator can output a burst signal based

on an external gate signal and the D3286 enables bit error measurement for burst condition data. This allows the fiber loop transmission test to be performed efficiently.

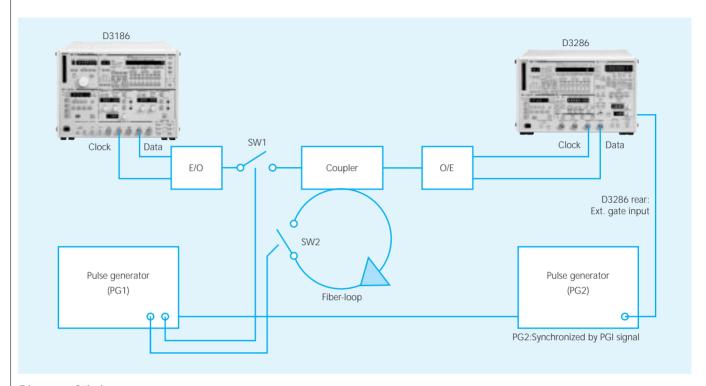
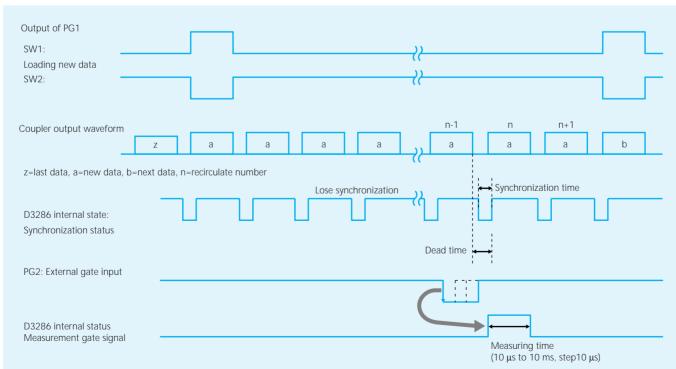
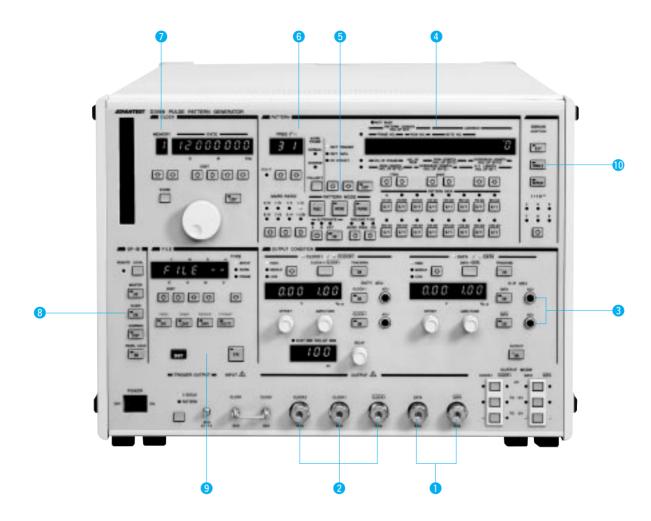


Diagram of timing



Front Panel Descriptions



D3186 Pulse Pattern Generator

1 Data output (DATA, DATA)

These connectors output the specified pattern in NRZ mode.

Amplitude range : 2 Vp-p, 3 Vp-p (option 15)

 $\begin{array}{ll} \text{Offset range} & : \pm 2 \text{ V} \\ \text{Tr/Tf} & : 30 \text{ ps or less} \\ \text{Jitter} & : 10 \text{ ps (typ.)} \\ \text{Overshoot, undershoot} : 5\% \text{ or less (typ.)} \end{array}$

2 Clock output (CLOCK1, CLOCK1, CLOCK2)

CLOCK1, CLOCK1,

These connectors output a clock signal with variable amplitude, offset, and delay.

Amplitude range : 2 Vp-p
Offset range : ±2 V

CLOCK2

This connector outputs an AC-coupled clock signal.

Amplitude range: About 1 Vp-p fixed

3 Cross point adjustment

Used to adjust the cross point position for DATA and \overline{DATA} outputs.

4 WORD pattern and frame pattern setup section

Used to set up WORD pattern and frame pattern. Selects up to 8 M-bit standard pattern memory allowing generation of 6 STM-64 frames.

5 Pattern mode setup section

Used to select the contents of the output pattern. WORD, PRBS, or FRAME (option 70) patterns can be selected.

6 Number-of-stages (N) selection key for PRBS

Applicable to 7 PRBS patterns with N of 7, 9, 10, 11, 15, 23, and 31.

7 Frequency setup section

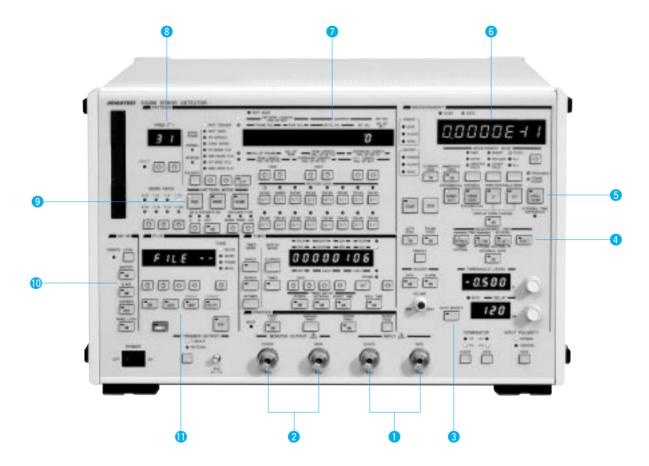
Used to select the operating clock frequency. Optionally, a high-purity clock source can be incorporated (option 10, 13). Up to 16 setup frequencies can be registered in the internal memory.

8 Remote control

The standard GPIB interface is mounted. The MASTER/SLAVE function allows pattern editing in conjunction with the D3286 error detector.

9 Disk operation section

The standard FD drive allows operating conditions and pattern setup conditions to be stored in floppy disks.



D3286 Error Detector

1 Data input section

• DATA

This input connector allows logic inversion.

Input amplitude : 0.1 to 2 Vp-p

Threshold level setup range : -2.040 to +2.040 V

Input sensitivity : 40 mV (typ.)

• CLOCK

Clock input connector

Input amplitude : 0.5 to 2 Vp-p

Variable amount of delay : Variable range ± 400 ps with respect to data

2 Monitor output

Monitor output for input data and clock. Waveform monitoring is possible during bit error measurement.

3 Auto search function

Used to automatically adjust the amount of delay for clock input and the threshold level of data input with a touch of key, simplifying complicated operations.

4 Measurement time mode selection section

The measurement time mode can be set to one of three modes: frame time, frame interval, and burst. Applicable to burst measurement time in SDH frame measurement and fiber loop test.

Measurement results display function setup

ERROR RATE, ERROR COUNT, EI, EFI, or FREQ/FRAME can be selected.

6Error measurement results display

Displays error measurement results with a display format dependent on the measurement function.

Pattern setup section

Used to edit data comparison pattern used in error measurement. The panel layout is the same as that of the D3186.

8 Number-of-stages (N) selection key for PRBS

Applicable to 7 PRBS patterns with N of 7, 9, 10, 11, 15, 23, and 31.

9Pattern mode selection section

Used to select data comparison pattern from PRBS, WORD, and FRAME (option 70) .

®Remote control

The standard GPIB interface is mounted. The MASTER/SLAVE function allows pattern editing in conjunction with the D3186 Pulse Pattern Generator.

1Disk operation section

The standard FD drive allows operating conditions and pattern setup conditions to be stored on floppy disks.

D3186 Specifications

Operating Clock

Operating clock source: Internal clock (optional), external clock

Internal Clock (optional)

150 MHz to 12 GHz (Option 10) Frequency range:

150 MHz to 12.5 GHz (Option 13)

Frequency setting resolution: 1 kHz Frequency stability: ±10 ppm/year

Output waveform: Sine wave, approx. 1 Vp-p Spurious: -37 dBc (non harmonic wave) SSB phase noise: -70 dBc/Hz (10 kHz offset, 12 GHz

carrier)

Frequency memory: 16 items Load impedance: 50Ω Connector: SMA (Jack)

Reference frequency output: 10 MHz, 1.5 Vp-p min., AC coupled,

BNC

10 MHz, 1.5 Vp-p min., AC coupled, Reference frequency input:

BNC, automatically switched

External Clock

Frequency range: 150 MHz to 12 GHz

150 MHz to 12.5 GHz (Option 72)

Input level: 0.7 Vp-p to 1.5 Vp-p

Input waveform: Sine wave

Main unit operating frequency range: 150 MHz to 12 GHz

150 MHz to 12.5 GHz (Option 72)

Patterns

Can be selected from the 3 choices below. Pattern Modes:

> Pseudo random pattern (PRBS) Fully programmable pattern (WORD) Frame pattern (FRAME) (Option 70)

PRBS

2^N-1, where N can be selected from Pattern length:

among

7 choices: N=7, 9, 10, 11, 15, 23 or 31

Number of stages N and generating function:

Number of stages	Generating function	Applied Standard
7	X ⁷ +X ⁶ +1	ITU-T recommended V.29
9	X9+X5+1	ITU-T recommended V.52
10	X ¹⁰ +X ⁷ +1	
11	X ¹¹ +X ⁹ +1	ITU-T recommended 0.152
15	X ¹⁵ +X ¹⁴ +1	ITU-T recommended 0.151
23	$X^{23}+X^{18}+1$	ITU-T recommended 0.151
31	$X^{31} + X^{28} + 1$	

Mark ratio: Can be selected from among

1/2, 1/4, 1/8, 0/8, 1/2B, 3/4, 7/8, or 8/8 The patterns 1/2B, 3/4, 7/8, and 8/8 are the logical inversions of the patterns 1/2, 1/4, 1/8 and 0/8

respectively.

AND bit Shift count: 1 bit

Word

Pattern length: 1 to 8,388,608 (223) bits (with ALTER-

NATE OFF)

1 to 4,194,304 (222) bits (with ALTER-

NATE ON)

Logical inversion: Possible

ALTERNATE mode: Can be turned ON/OFF; When ON,

can be switched to either of 2 patterns,

A or B

Switching control: Internal, external switching possible Internal switching: Done by front panel keys or GPIB External switching: Done by external alternate input signal FRAME (Option 70)

Payload format: 3 types below can be selected Fully programmable (WORD)

Pseudo random (PRBS)

0/1 continuous pattern + PRBS (CID)

Frame structure:

When payload format is WORD or PRBS:

Number of frames: 1 to 8,192 (with ALTERNATE OFF)

1 to 4,096 (with ALTERNATE ON)

1 frame steps

Number of lines in 1 frame: 1 to 16 (1 line steps)

Number of bytes in 1 line: 44 to 32,768

Number of overhead bytes in 1 line: 4 to (number of bytes in 1 line - 40

bytes), 4 byte steps

When payload format is CID:

Number of bites in 1 line: 40 to 32,768, 4 byte steps

Number of overhead bytes in 1 line: 36 to (number of bytes in 1 line+integer

quotient of 36)×36, 36 byte steps

Number of 0/1 continuous pattern bits:

0 to (number of bytes in 1 line - number of overhead bytes in 1 line)×8 bits, 1 bit

steps

Stage Number of PRBS: 7, discontinuous parts may exist

Logical inversion: Possible

ALTERNATE mode: Can be turned ON/OFF (only when

payload type is WORD or PRBS); When ON, can be switched to either of 2

patterns. A or B

Switching control: Internal, external switching possible Internal switching: Done by front panel keys or GPIB External switching: Done by external alternate input signal

Error Addition

Error addition mode: Repeat, single, external

Error ratio 1×10^{-N} , N=4 to 9, bit error is Repeat:

added at a set interval

1 bit error is added with every error Single:

addition command

External: 1 bit error is added with every falling

edge of an external error addition pulse

input

Main Outputs

Number of outputs: Data, 2 patterns (DATA, DATA)

Clock, 3 patterns (CLOCK1, CLOCK1,

CLOCK2)

Data Outputs (DATA, DATA)

Number of outputs: 2 patterns (DATA, DATA,

complementary) NRZ

Format: Coupling: DC

Amplitude range: 0.5 Vp-p to 2 Vp-p, 10 mV steps

(TO 0 V, AC)

0.6 Vp-p to 1 Vp-p, 10 mV steps

(TO -2 V)

(Option 15): 0.5 Vp-p to 3 Vp-p, 10 mV steps

(TO 0 V)

0.5 Vp-p to 2 Vp-p, 10 mV steps

(TO AC)

0.6 Vp-p to 1 Vp-p, 10 mV steps

Offset range: -2 V to +2 V, 10 mV steps (TO 0 V) -1 V to -0.6 V, 10 mV steps (TO -2 V)

-1 V to +1 V, 10 mV steps (TO 0 V)

(Option 15): -1 V to -0.6 V, 10 mV steps (TO -2 V)

Rise/fall time: 30 ps max.

Can be selected as either DC coupled Load terminal conditions:

TO 0 V, TO -2 V or AC coupled Can be selected as either HIGH,

Offset setting level: MIDDLE or LOW

> ON/OFF selectable GPIB selectable

Load impedance: 50Ω

Cross point variable:

Connector: 2.92 mm (plug)

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Clock Outputs (CLOCK1, CLOCK1)

Number of outputs: 2 patterns (CLOCK1, CLOCK1,

complementary)

Format: RZ Coupling: DC

Amplitude range: 0.5 Vp-p to 2 Vp-p, 10 mV steps (TO

0 V, AC)

 $0.6\ Vp\mbox{-p}$ to $1\ Vp\mbox{-p},\ 10\ mV$ steps (TO

-2 V)

Offset range: -2 V to +2 V, 10 mV steps (TO 0 V)

-1 V to -0.6 V, 10 mV steps (TO -2 V)

(HIGH level reference)

Rise/fall tame: 30 ps max

Load terminal conditions: Can be selected as either DC coupled

TO 0 V, TO -2 V or AC coupled

Offset setting level: Can be selected as either HIGH,

MIDDLE or LOW

Duty ratio variable: ON/OFF selectable

Variable delay range: ± 400 ps, 1 ps steps (CLOCK2 output

reference)

Load impedance: 50Ω

Connector: 2.92 mm (plug)

Clock Output (CLOCK2)

Number of outputs: 1 pattern Format: RZ

Coupling: AC (built-in DC blocking condenser)

Amplitude: Approx. 1 Vp-p fixed

Offset: $0 \text{ V} \pm 0.1 \text{ V}$ fixed (MIDDLE level

reference)

 $\begin{array}{lll} Waveform: & Rectangular \ wave \\ Rise/fall \ time: & 30 \ ps \ max \\ Load \ impedance: & 50 \ \Omega \\ \end{array}$

Connector: 2.92 mm (plug)

Trigger Signal Output

Output Signal: Can be selected as either clock

 $synchronization\ or\ pattern$

synchronization

Clock synchronization (1/32 CLK): Clock frequency 1/32 divided output

Pattern synchronization

(PATTERN): Varies output position to any position in

16 bit units

Output level: HIGH level 0 V ± 0.2 V, LOW level

-1 V ±0.2 V

 $\begin{array}{ll} \mbox{Load impedance:} & 50~\Omega~\mbox{to}~0~\mbox{V} \\ \mbox{Connector:} & \mbox{SMA} \end{array}$

Auxiliary Output

1/2 Clock Output

Format: RZ Coupling: DC

Output level: HIGH level, 0 V±0.2 V, LOW level

-1 V ± 0.2 V

 $\begin{array}{ll} \mbox{Load impedance:} & 50~\Omega~\mbox{to}~0~V \\ \mbox{Connector:} & \mbox{SMA} \end{array}$

1/4 Rate Output

Output bit rate: 1/4 operating clock frequency

Number of pattern outputs: 4 patterns
Number of clock outputs: 1 pattern
Output skew: ±150 ps max.

Output level: HIGH level 0 V ± 0.25 V , LOW level

 $-1~V~\pm0.25~V$

 $\begin{array}{ll} \mbox{Load impedance:} & 50~\Omega~\mbox{to}~0~V \\ \mbox{Connector:} & \mbox{SMA} \end{array}$

Control Input

External Gate Input

Function: Inhibits data output, inhibits at LOW

level

Input level: 0 V/-1 V

Input pulse width: At least 20 ns, or at least 64 x operating

clock cycle, whichever is longer

Input impedance: Approx. 50Ω to 0 V

Connector: BNC

External Alternate Input

Function: In ALTERNATE mode, switches

between patterns A and B; pattern A at HIGH level, Pattern B at LOW level

Input level: 0 V/-1 V

Input impedance: Approx. 50 Ω to 0 V

Connector: BNC

External Error Addition

Function: When pattern error addition is

external (EXT), 1 bit error is added for

every fall edge of the input pulse

Input level: 0 V/-1 V

Input impedance: Approx. 50Ω to 0 V

Connector: BNC

System Functions

Master/Slave Function

Function: When used together with the D3286

Error Detector, allows the pattern settings of the D3186 and D3286 to be

interlocked.

Panel Lock: possible External Clock Generator Control Function

Function: When external clock generator (SG) is

used, the frequency and output level are

controlled from the D3186

Connection method: Dedicated GPIB connector

Remote Control

Interface: GPIB (IEEE 488-1978)

Calender/Clock Function

Display: Can be selected as either

year/month/day/hour or day/hour/minute/second

File Function: Built-in floppy disk drive

Functions: Save, re-save, read in, erase and initialize Saved data: Operating conditions, pattern settings Read in data: Operating conditions, pattern settings Disks used: 3.5 inch floppy disks, 720 KB (2DD), 1.2 MB (2HD), 1.4 MB (2HD)

Disk format: MS-DOS® Rev. 4.0 File format: Proprietary binary format

MS-DOS is a registered trademark of Microsoft Corporation.

General Specifications

Numerical value display: Green 7 segment LED display

Set conditions memory: After power has been ON for 12 hours,

retained at least 2 weeks (backed up by

secondary battery)

Operating temperature range: $0^{\circ}\text{C to} + 40^{\circ}\text{C}$

+20°C to +30°C (Option 72)

Operating humidity range: 40% to 85% RH Storage temperature range: -20°C to +60°C

Storage humidity range: 30% to 85% RH (without condensation)

Power: AC 100 V to 120 V, AC 220 V to

240 V (switches automatically) 48 to 63 Hz, sine wave

550 VA max.

Power consumption: 550 VA max. Mass: 42 kg max.

External dimensions: Approx. 310 (H)×424 (W)×

550 (D) mm

	Stand	lard A	Accessori	es
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Name	Туре	Stock No.	Quantity	Remarks
Power Cable	A01402	DCB-DD2428X01	1	
SMA-SMA Cable	DGM224-00700A	DCB-FF1211X01	7	
GPIB Cable	408JE-101	DCB-SS1076X02	1	
3 Pin- 2 Pin Converter Adapter For Power Plug	A09034	JCD-AL003EX03	1	
2.92 mm Adapter	02K121-K00S3	JCF-BJ001EX05	5	
User's Manual		JD3186 ED3186	1	Japanese English

D3286 Specifications

Operating Frequency

Operating Frequency Range: 150 MHz to 12 GHz

150 MHz to 12.5 GHz (Option 72)

Measuring Functions

Reference Measuring Functions:

Simultaneous measurement of 6

functions, 1 function can be selected for

display

Error rate measurement Error count measurement Error interval (EI) measurement Error free interval (EFI) measurement

Frequency measurement Frame count measurement:

Frame count measurement can only be done when the pattern mode is FRAME, the payload format is WORD or PRBS, and the measuring time mode is FRAME TIME (FR. TIME) or FRAME

INTERVAL (FR. INTV)

Display Format: Synchronous measurement

Error rate measurement (1 type fixed)

Exponential format: Displays the number of error bits per

number of input bits

Up to 5 digit mantissa + exponent

Error count measurement (2 types, 1 type can be selected for

display)

Exponential format: Displays the number of error bits in

exponential format

Up to 5 digit mantissa + exponent Displays the lowest 8 digits of the

number of error bits as an integer

Error interval measurement (2 types, 1 type can be selected

for display)

Integer format:

% format: Displays the number of error intervals

per number of measured intervals as a fixed decimal point percentage Up to 3 digit integer part + 4 digit

decimal part

Number of interval format: Display the number of error intervals in

exponential format

Up to 5 digit mantissa + exponent

Error free interval (EFI) measurement (2 types, 1 type can be

selected for display)

% format: Displays the number of error free

intervals as a fixed decimal point

percentage

Up to 3 digit integer part + 4 digit

decimal part

Number of interval format: Displays the number of error free

intervals in exponential format Up to 5 digit mantissa + exponent

Frequency measurement (1 type fixed)

Fixed decimal point: Displays the frequency of the input clock

in MHz units in fixed decimal point

format

Up to 5 digit integer part + 3 digit

decimal part

Number of frames measurement (1 type fixed)

Exponent format: Converts the number of input bits to a

number of frames and displays this

number

Up to 5 digit mantissa + exponent

Error Measurement Mode: 3 groups can be selected, within each

group three types of measurements can be done simultaneously, and one type

displayed

Omission/Insertion Group

OMISSION: Displays the measured value of errors of

the sort when logical data value of '0' is input when '1' is the expected value

INSERTION: Displays the measured value of errors of

the sort when logical data value of '1' is input when '0' is the expected value

Displays the measured value of the sum of OMISSION and INSERTION type

errors (all errors).

Overhead/Payload Group

TOTAL:

Can only be selected when the pattern mode is FRAME

OVERHEAD: Displays the measured value of errors in

the overhead part.

PAYLOAD: Displays the measured value of errors in

the payload part.

ALL: Displays the measured value of sum of

the errors in the overhead part and payload part (all frame errors).

Specific field group

Can only be selected when the pattern mode is WORD or FRAME

SPECIFIC FIELD: Displays the measured value of errors

within a specified specific field.

OTHER FIELD: Displays the measured value of errors

within the fields other than the specified

specific field.

ALL: Displays the measured value of the sum

of the errors in the specific field and the

other fields (all pattern errors)

Midway Results Display: ON/OFF selectable

Threshold EF/EFI Measurement:

Measured results can only be given as printer output and file record Measures simultaneously with the reference

measurement function

Error Performance Measurement:

Measured results can only be given as

printer output and file record

Measurement items (the 5 items below are measured simultaneously with the reference measurement function)

ES:Errored Seconds EFS: Error Free Seconds SES: Severely Errored Seconds US:Unavailable Seconds DM:Degraded Minutes

Measurement Control

START: Starts simultaneous measurement of all

measuring functions, or measurement interrupt and re-start. Can be done with front panel keys, GPIB or external gate

input signal.

STOP: Stops simultaneous measurement of all

measuring functions. Can be operated through front panel keys, GPIB built-in timer, or external gate input signal.

Measuring Time Mode: Any of 4 types can be selected

NORMAL: Sets measurement interval in seconds

units, measurement period in day/hour/minute/second units.

FR. TIME: Can only be selected when pattern mode

is FRAME. Measuring interval is set in number of frame units and measuring period is set in day/hour/minute/second

units.

FR. INTV: Can only be selected when pattern mode

is FRAME. Measuring interval is set in number of frame units and measuring period is set in number of measuring

interval units.

BURST: Each time pattern synchronization is

established during the period from measuring start to measuring end, only the area set by the burst timer is

measured.

Mask Function: Can only be selected when pattern mode

is WORD or FRAME.

Synchronization and measurement are done ignoring errors in the specified

mask field.

Pattern Synchronization

Auto synchronization: ON/OFF selectable

When ON, re-synchronization is done automatically when the error rate is equal to or greater than the prescribed value.

Frame synchronization: Can be turned ON or OFF when pattern

mode is FRAME or WORD. Set OFF during PRBS.

When ON, the specified hunting pattern

is searched and high speed pattern

synchronization is done.

Re-synchronization: Command can be given using front panel

keys or GPIB.

Measurement Conditions Display Lamp

GATE: Lights during measurement.

OVER: Lights when measurement results

overflow.

Error Alarm Display Lamp

DATA error: Lights when a 1 or more bit error is

detected.

Goes out when error is no longer

detected.

CLOCK error: Lights when the input clock fails or

frequency is too low.

Goes out when normal clock is input.

Lights when there is a pattern

synchronization error.

Goes out when pattern synchronization is

established.

History Display Lamp

SYNC error:

POWER fail: Lights after power is restored after a

power failure. Stays lit until the next

measurement stars.

CLOCK error: Lights when the input clock fails or

frequency is too low. After the error is recovered, lights until the next

covered, lights diffil the flext

 $measurement\ starts.$

SYNC error: Lights when there is a pattern

synchronization error. After the error is

recovered, lights until the next

measurement starts.

Buzzer

Error: Sounds when there is a DATA error. Can

be set to ON/OFF. Volume variable

(same as alarm volume).

Alarm: Sounds when there is a CLOCK or

SYNC error. Can be set to ON/OFF. Volume variable (same as error volume).

Measurement Input

Data Input

Input format: DC termination, DC coupling

Code: NRZ

Polarity: Logical inversion possible Input amplitude: 0.1 Vp-p to 2 Vp-p

Threshold level: Setting range -2.040 V to + 2.040 V

Setting resolution 0.001 V steps (with

0 V terminal voltage)

Setting range -1.850 V to -0.750 V Setting resolution 0.001V steps(with

-2 V terminal voltage)

Terminal voltage: -2 V/0 V (GND)Input impedance: Approx. 50Ω Connector: 2.92 mm (plug)

Clock Input

Input format: DC termination, AC coupling

Duty ratio: $50\% \pm 5\%$

Polarity: Identified at rise edge

Variable delay: $\pm 400 \text{ ps } 1 \text{ ps steps (at monitor output)}$

 $\begin{array}{lll} \mbox{Input amplitude:} & 0.5 \mbox{ Vp-p to 2 Vp-p} \\ \mbox{Terminal voltage:} & -2 \mbox{ V/0 V (GND)} \\ \mbox{Input impedance:} & \mbox{Approx. 50 } \Omega \\ \mbox{Connector:} & 2.92 \mbox{ mm (plug)} \\ \end{array}$

Input waveform: Sine wave or rectangular wave

Auto Search Function

Automatically finds the optimum values for data input threshold level and

clock input delay.

Trigger Signal Output

Output Signal: Can be selected as either clock

synchronization or pattern

synchronization

Clock synchronization (1/32 CLK): Clock frequency 1/32 divided output

Pattern synchronization

(PATTERN): Varies output position to any position in

16 bit units

Output level: HIGH level 0 V \pm 0.2 V, LOW level

-1 V ± 0.2 V

Auxiliary Output

Monitor Output

Data monitor: Outputs data input through amplifier Load impedance: 50 Ω to 0 V

Connector: 2.92 mm (plug)

Clock monitor: Outputs clock input through amplifier

and variable delay line

Load impedance: 50Ω to 0 VConnector: 2.92 mm (plug)

Error Output

Direct output

Rate: 1/32 of clock input Signal form: 32 phase logical sum

Code: RZ

Output voltage: HIGH level $-0.0 \pm 0.3 \text{ V}$

LOW level $-1.0 \pm 0.3 \text{ V}$

Load impedance: 50Ω to 0 VConnector: SMA (jack)

Stretched output

Control Input

External Gate Input

Function: Controls measurement start/stop

Input level: 0 V/-1 V

Input impedance: Approx. 50Ω to 0 V Connector: BNC (jack)

External Alternate Input

Function: Switches between patterns A and B in

alternate mode. Pattern A at HIGH level.

pattern B at LOW level.

Input level: 0 V/-1 V

Input impedance: Approx. 50Ω to 0 V

Connector: BNC (jack)

Patterns

Same as for the D3186 Pulse Pattern Generator

Timer/Clock

Timer/Clock Display

ELAPSED: Displays the elapsed time since the start

of measurement.

TIMED: Displays the remaining time until the

end of measurement.

PERIOD: Displays or sets the measuring period

from the start of measurement until the

end.

INTERVAL: Displays or sets the measuring cycle.

BURST TIME: Displays or sets the measuring time per signal burst when the measuring time

mode is BURST.

REAL TIME: Displays or sets real time as

year/month/day/hour or day/hour/minute/second.

Timer Mode

SINGLE: When the set period of measurement has

elapsed, the measurement is stopped.

REPEAT: When the set period of measurement has

elapsed, a new measurement is begun. The sequence is repeated until a

command to stop is received.

UNTIMED: Measurement continues regardless of the

set measuring period, until the command

to stop is given.

Time Reference Clocks: Internal, external, selected automatically

Internal clock stability: 10 ppm/year

External clock input: 10 MHz, 1 Vp-p , AC coupled

Connector: BNC (Jack)

System Functions

Printer: Measurement results can be output to an

external printer

External printer interface:

Standard specification: Centronics specification
Connector: 36 pin micro ribbon

File Function: Same as for the D3186 Pulse Pattern

Generator and possible to save

measurement results
MS-DOS® text format

Measurement results: Remote Control

Interface: GPIB (IEEE 488-1978)

Master/Slave Function

Function: When used together with the D3186

Pulse Pattern Generator, allows the pattern settings of the D3186 and D3286

to be interlocked.

Connection method: Connected by GPIB cable, through each

GPIB connector

Panel Lock: Can lock all condition settings except

power ON/OFF, panel lock ON/OFF, GPIB Local return, rear panel DIP switch

settings, and buzzer volume level.

General Specifications

Numerical value display: Green 7 segment LED display

Set conditions memory: After power has been ON for 12 hours, retained at least 2 weeks (backed up by

secondary battery)

Operating temperature range: $0^{\circ}\text{C to } +40^{\circ}\text{C}$

+20°C to +30°C (Option 72)

Operating humidity range: 40% to 85% RH Storage temperature range: -20°C to +70°C

Storage humidity range: 30% to 85% RH (without condensation)

AC 100 V to 120 V, AC 220 V to 240 V

(switches automatically) 48 to 63 Hz,

sine wave

Power consumption: 500 VA max. Mass: 32 kg max.

External dimensions: Approx. 266 (H)×424 (W)×

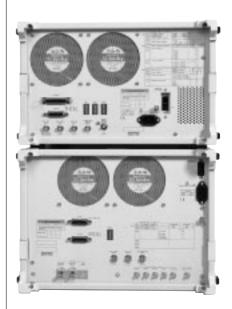
550 (D) mm

Standard Accessories

Power:

Name	Туре	Stock No.	Quantity	Remarks
Power Cable	A01402	DCB-DD2428X01	1	
SMA-SMA Cable	DGM224-00700A	DCB-FF1211X01	3	
GPIB Cable	408JE -101	DCB-SS1076X02	1	
3 Pin - 2 Pin Converter Adapter For Power Plug	A09034	JCD-AL003EX03	1	
2.92 mm Adapter	02K121-K00S3	JCF-BJ001EX05	4	,
User's Manual		JD3286 ED3286	1	Japanese English

Please be sure to read the manual of product thoroughly before using the products. Specifications may change without notification.



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